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Understanding [Embedded - DSP \(Digital Signal Processors\)](#)

[Embedded - DSP \(Digital Signal Processors\)](#) are specialized microprocessors designed to perform complex mathematical computations on digital signals in real-time. Unlike general-purpose processors, DSPs are optimized for high-speed numeric processing tasks, making them ideal for applications that require efficient and precise manipulation of digital data. These processors are fundamental in converting and processing signals in various forms, including audio, video, and communication signals, ensuring that data is accurately interpreted and utilized in embedded systems.

Applications of [Embedded - DSP \(Digital Signal Processors\)](#)

Details

Product Status	Obsolete
Type	SC1400 Core
Interface	Host Interface, I ² C, UART
Clock Rate	200MHz
Non-Volatile Memory	External
On-Chip RAM	208kB
Voltage - I/O	3.30V
Voltage - Core	1.20V
Operating Temperature	-40°C ~ 105°C (TJ)
Mounting Type	Surface Mount
Package / Case	400-LFBGA
Supplier Device Package	400-LFBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/msc7113vm800

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Table 1. MSC7113 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
B15 (1L44X)	NC					
B15 (1M88B)	BM2	GPID7		GPOD7	reserved	
B16	NC					
B17	NC					
B18	NC					
B19	NC					
B20	NC					
C1	D24					
C2	D30					
C3	D25					
C4	$\overline{\text{CS1}}$					
C5	DQM3					
C6	DQM0					
C7	DQS1					
C8	$\overline{\text{RAS}}$					
C9	$\overline{\text{CAS}}$					
C10	GPIC5			GPOC5	HD13	
C11	GPIC1			GPOC1	HD9	
C12	reserved				HD3	
C13	NC					
C14	NC					
C15	NC					
C16	NC					
C17	NC					
C18	NC					
C19	NC					
C20	NC					
D1	V_{DDM}					
D2	D28					
D3	D27					
D4	GND					
D5	V_{DDM}					
D6	V_{DDM}					
D7	V_{DDM}					
D8	V_{DDM}					
D9	V_{DDM}					
D10	V_{DDM}					
D11	V_{DDIO}					

Table 1. MSC7113 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
R18	TDO					
R19	reserved			EE0/DBREQ		
R20	TEST0					
T1	V _{DDM}					
T2	D20					
T3	D22					
T4	V _{DDM}					
T5	V _{DDM}					
T6	V _{DDC}					
T7	V _{DDM}					
T8	V _{DDM}					
T9	V _{DDC}					
T10	V _{DDM}					
T11	V _{DDM}					
T12	V _{DDIO}					
T13	V _{DDIO}					
T14	V _{DDIO}					
T15	V _{DDIO}					
T16	V _{DDC}					
T17	V _{DDC}					
T18	reserved			MDIO		
T19	TMS					
T20	HRESET					
U1	GND					
U2	D21					
U3	D23					
U4	V _{DDM}					
U5	V _{DDC}					
U6	V _{DDC}					
U7	V _{DDC}					
U8	V _{DDC}					
U9	V _{DDC}					
U10	V _{DDC}					
U11	V _{DDC}					
U12	V _{DDC}					
U13	V _{DDC}					
U14	V _{DDC}					
U15	V _{DDC}					

Table 1. MSC7113 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
U16	V _{DDC}					
U17	V _{DDC}					
U18	reserved				COL	
U19	TCK					
U20	$\overline{\text{TRST}}$					
V1	V _{DDM}					
V2	NC					
V3	A13					
V4	A11					
V5	A10					
V6	A5					
V7	A2					
V8	BA0					
V9	NC					
V10	reserved				EVNT0	
V11	SWTE	GPIA16	$\overline{\text{IRQ12}}$	GPOA16	EVNT4	
V12	GPIA8		$\overline{\text{IRQ6}}$	GPOA8	T0TCK	
V13	GPIA4		$\overline{\text{IRQ1}}$	GPOA4	T1RFS	
V14	GPIA0		$\overline{\text{IRQ11}}$	GPOA0	T1TD	
V15	GPIA28		$\overline{\text{IRQ17}}$	GPOA28	TX_ER	reserved
V16	GPID6			GPOD6	RXD2	reserved
V17	GPIA22		$\overline{\text{IRQ22}}$	GPOA22	RXD0	
V18	GPIA24		$\overline{\text{IRQ24}}$	GPOA24	TX_EN	
V19	reserved				CRS	
V20	TDI					
W1	GND					
W2	V _{DDM}					
W3	A12					
W4	A8					
W5	A7					
W6	A6					
W7	A3					
W8	NC					
W9	GPIA17		$\overline{\text{IRQ13}}$	GPOA17	EVNT1	CLKO
W10	BM0	GPIC14		GPOC14	EVNT2	
W11	GPIA10		$\overline{\text{IRQ5}}$	GPOA10	T0RFS	
W12	GPIA7		$\overline{\text{IRQ7}}$	GPOA7	T0TFS	
W13	GPIA3		$\overline{\text{IRQ8}}$	GPOA3	T1RD	

2.2 Recommended Operating Conditions

Table 3 lists recommended operating conditions. Proper device operation outside of these conditions is not guaranteed.

Table 3. Recommended Operating Conditions

Rating	Symbol	Value	Unit
Core supply voltage	V_{DDC}	1.14 to 1.26	V
Memory supply voltage	V_{DDM}	2.38 to 2.63	V
PLL supply voltage	V_{DDPLL}	1.14 to 1.26	V
I/O supply voltage	V_{DDIO}	3.14 to 3.47	V
Reference voltage	V_{REF}	1.19 to 1.31	V
Operating temperature range	T_J T_A	maximum: 105 minimum: -40	°C °C

2.3 Thermal Characteristics

Table 4 describes thermal characteristics of the MSC7113 for the MAP-BGA package.

Table 4. Thermal Characteristics for MAP-BGA Package

Characteristic	Symbol	MAP-BGA 17 × 17 mm ⁵		Unit
		Natural Convection	200 ft/min (1 m/s) airflow	
Junction-to-ambient ^{1, 2}	$R_{\theta JA}$	39	31	°C/W
Junction-to-ambient, four-layer board ^{1, 3}	$R_{\theta JA}$	23	20	°C/W
Junction-to-board ⁴	$R_{\theta JB}$	12		°C/W
Junction-to-case ⁵	$R_{\theta JC}$	7		°C/W
Junction-to-package-top ⁶	Ψ_{JT}	2		°C/W
Notes: 1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance. 2. Per SEMI G38-87 and JEDEC JESD51-2 with the single layer board horizontal. 3. Per JEDEC JESD51-6 with the board horizontal. 4. Thermal resistance between the die and the printed circuit board per JEDEC JESD 51-8. Board temperature is measured on the top surface of the board near the package. 5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1). 6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.				

Section 3.1, *Thermal Design Considerations* explains these characteristics in detail.

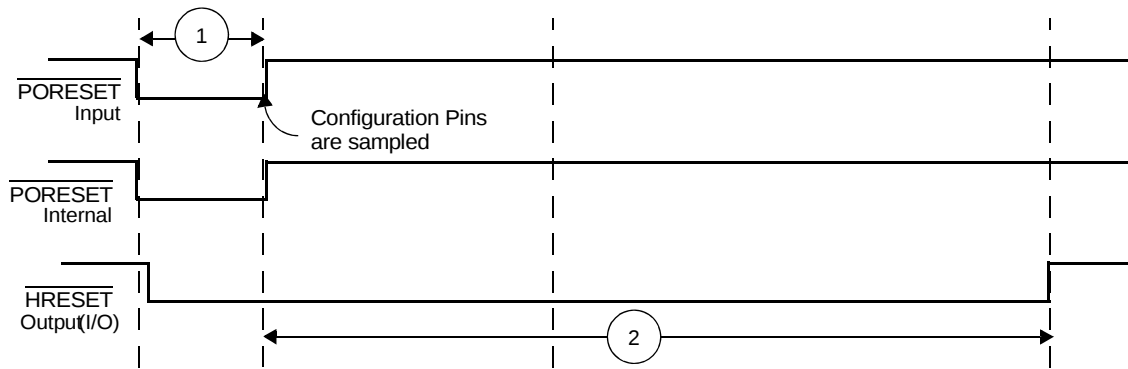


Figure 4. Timing Diagram for a Reset Configuration Write

2.5.4 DDR DRAM Controller Timing

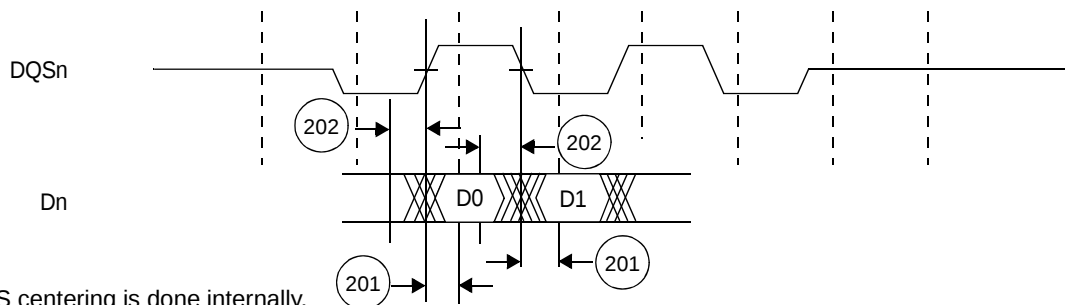
This section provides the AC electrical characteristics for the DDR DRAM interface.

2.5.4.1 DDR DRAM Input AC Timing Specifications

Table 17 provides the input AC timing specifications for the DDR DRAM interface.

Table 17. DDR DRAM Input AC Timing

No.	Parameter	Symbol	Min	Max		Unit
				Mask Set 1L44X	Mask Set 1M88B	
—	AC input low voltage	V_{IL}	—	$V_{REF} - 0.31$	$V_{REF} - 0.31$	V
—	AC input high voltage	V_{IH}	$V_{REF} + 0.31$	$V_{DDM} + 0.3$	$V_{DDM} + 0.3$	V
201	Maximum Dn input setup skew relative to DQSn input	—	—	1026	900	ps
202	Maximum Dn input hold skew relative to DQSn input	—	—	386	900	ps
Notes: - Maximum possible skew between a data strobe (DQSn) and any corresponding bit of data (D[8n + {0...7}]) if $0 \leq n \leq 7$. - See Table 18 for t_{CK} value. - Dn should be driven at the same time as DQSn. This is necessary because the DQSn centering on the DQn data tenure is done internally.						



Note: DQS centering is done internally.

Figure 5. DDR DRAM Input Timing Diagram

Table 20. TDM Timing

No.	Characteristic	Expression	Min	Max	Units
307	TDMxTCK High to TDMxTD output valid		—	14.0	ns
308	TDMxTD hold time		2.0	—	ns
309	TDMxTCK High to TDMxTD output high impedance		—	10.0	ns
310	TDMxTFS/TDMxRFS output valid		—	13.5	ns
311	TDMxTFS/TDMxRFS output hold time		2.5	—	ns
Notes: 1. Output values are based on 30 pF capacitive load. 2. Inputs are referenced to the sampling that the TDM is programmed to use. Outputs are referenced to the programming edge they are programmed to use. Use of the rising edge or falling edge as a reference is programmable. Refer to the <i>MSC711x Reference Manual</i> for details. TDMxTCK and TDMxRCK are shown using the rising edge.					

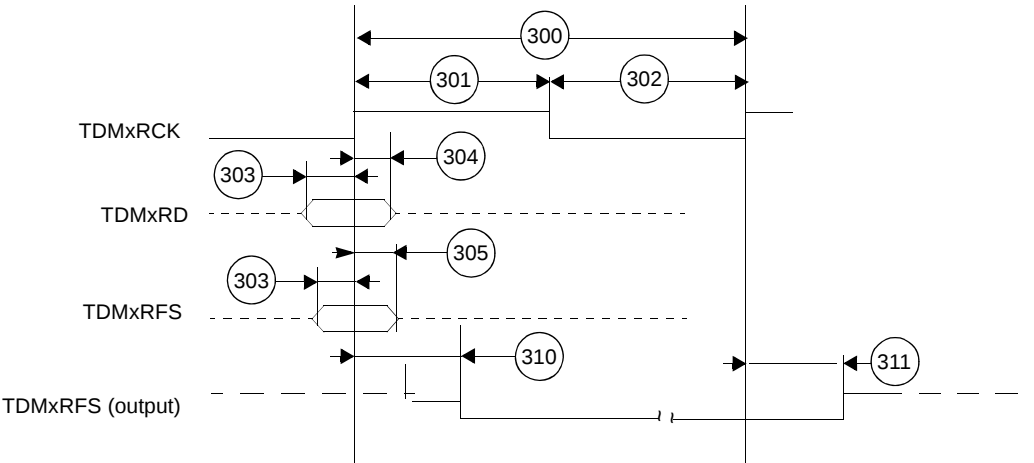


Figure 8. TDM Receive Signals

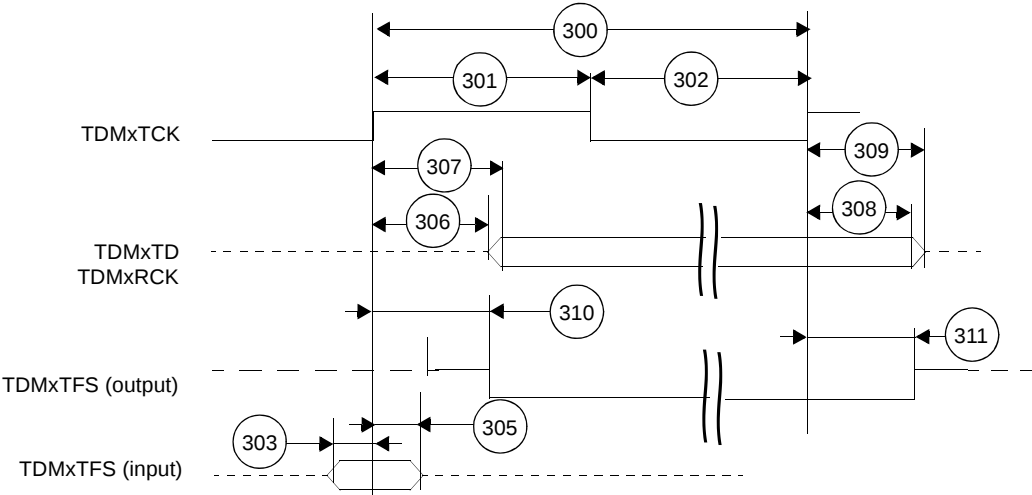


Figure 9. TDM Transmit Signals

2.5.6 Ethernet Timing

2.5.6.1 Receive Signal Timing

Table 21. Receive Signal Timing

No.	Characteristics	Min	Max	Unit
800	Receive clock period: • MII: RXCLK (max frequency = 25 MHz) • RMII: REFCLK (max frequency = 50 MHz)	40 20	— —	ns ns
801	Receive clock pulse width high—as a percent of clock period • MII: RXCLK • RMII: REFCLK	35 14 7	65 — —	% ns ns
802	Receive clock pulse width low—as a percent of clock period: • MII: RXCLK • RMII: REFCLK	35 14 7	65 — —	% ns ns
803	RXDn, RX_DV, CRS_DV, RX_ER to receive clock rising edge setup time	4	—	ns
804	Receive clock rising edge to RXDn, RX_DV, CRS_DV, RX_ER hold time	2	—	ns

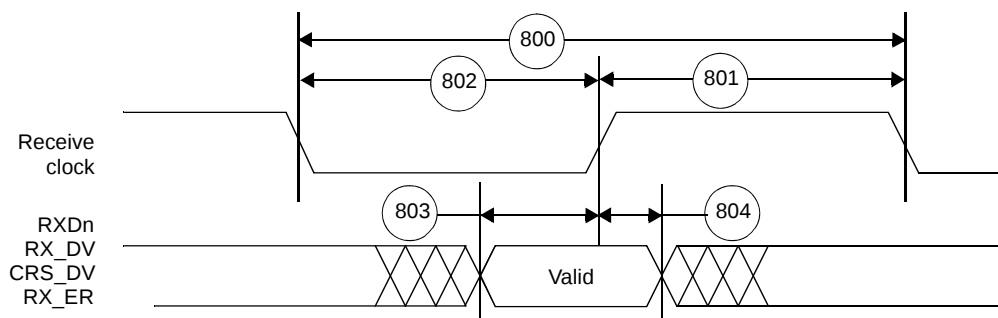


Figure 10. Ethernet Receive Signal Timing

2.5.7 HDI16 Signals

Table 25. Host Interface (HDI16) Timing^{1, 2}

No.	Characteristics ³	Mask Set 1L44X		Mask Set 1M88B		Unit
		Expression	Value	Expression	Value	
40	Host Interface Clock period	T_{HCLK}	Note 1	T_{CORE}	Note 1	ns
44a	Read data strobe minimum assertion width ⁴ HACK read minimum assertion width	$3.0 \times T_{HCLK}$	Note 11	$2.0 \times T_{CORE} + 9.0$	Note 11	ns
44b	Read data strobe minimum deassertion width ⁴ HACK read minimum deassertion width	$1.5 \times T_{HCLK}$	Note 11	$1.5 \times T_{CORE}$	Note 11	ns
44c	Read data strobe minimum deassertion width ⁴ after "Last Data Register" reads ^{5,6} , or between two consecutive CVR, ICR, or ISR reads ⁷ HACK minimum deassertion width after "Last Data Register" reads ^{5,6}	$2.5 \times T_{HCLK}$	Note 11	$2.5 \times T_{CORE}$	Note 11	ns
45	Write data strobe minimum assertion width ⁸ HACK write minimum assertion width	$1.5 \times T_{HCLK}$	Note 11	$1.5 \times T_{CORE}$	Note 11	ns
46	Write data strobe minimum deassertion width ⁸ HACK write minimum deassertion width after ICR, CVR and Data Register writes ⁵	$2.5 \times T_{HCLK}$	Note 11	$2.5 \times T_{CORE}$	Note 11	ns
47	Host data input minimum setup time before write data strobe deassertion ⁸ Host data input minimum setup time before $\overline{\text{HACK}}$ write deassertion	—	3.0	—	2.5	ns
48	Host data input minimum hold time after write data strobe deassertion ⁸ Host data input minimum hold time after $\overline{\text{HACK}}$ write deassertion	—	4.0	—	2.5	ns
49	Read data strobe minimum assertion to output data active from high impedance ⁴ HACK read minimum assertion to output data active from high impedance	—	1.0	—	1.0	ns
50	Read data strobe maximum assertion to output data valid ⁴ HACK read maximum assertion to output data valid	$(2.0 \times T_{HCLK}) + 8.0$	Note 11	$(2.0 \times T_{CORE}) + 8.0$	Note 11	ns
51	Read data strobe maximum deassertion to output data high impedance ⁴ HACK read maximum deassertion to output data high impedance	—	8.0	—	9.0	ns
52	Output data minimum hold time after read data strobe deassertion ⁴ Output data minimum hold time after $\overline{\text{HACK}}$ read deassertion	—	1.0	—	1.0	ns
53	HCS[1–2] minimum assertion to read data strobe assertion ⁴	—	0.0	—	0.5	ns
54	HCS[1–2] minimum assertion to write data strobe assertion ⁸	—	0.0	—	0.0	ns
55	HCS[1–2] maximum assertion to output data valid	$(2.0 \times T_{HCLK}) + 8.0$	Note 11	$(2.0 \times T_{CORE}) + 6.0$	Note 11	ns
56	HCS[1–2] minimum hold time after data strobe deassertion ⁹	—	0.0	—	0.5	ns
57	HA[0–3], HRW minimum setup time before data strobe assertion ⁹	—	5.0	—	5.0	ns
58	HA[0–3], HRW minimum hold time after data strobe deassertion ⁹	—	5.0	—	5.0	ns
61	Maximum delay from read data strobe deassertion to host request deassertion for "Last Data Register" read ^{4, 5, 10}	$(3.0 \times T_{HCLK}) + 8.0$	Note 11	$(3.0 \times T_{CORE}) + 6.0$	Note 11	ns
62	Maximum delay from write data strobe deassertion to host request deassertion for "Last Data Register" write ^{5,8,10}	$(3.0 \times T_{HCLK}) + 8.0$	Note 11	$(3.0 \times T_{CORE}) + 6.0$	Note 11	ns
63	Minimum delay from DMA HACK (OAD=0) or Read/Write data strobe(OAD=1) deassertion to HREQ assertion.	$(2.0 \times T_{HCLK}) + 1.0$	Note 11	$(2.0 \times T_{CORE}) + 1.0$	Note 11	ns
64	Maximum delay from DMA HACK (OAD=0) or Read/Write data strobe(OAD=1) assertion to HREQ deassertion	$(5.0 \times T_{HCLK}) + 8.0$	Note 11	$(5.0 \times T_{CORE}) + 6.0$	Note 11	ns

2.5.9 UART Timing

Table 27. UART Timing

No.	Characteristics	Expression	Mask Set 1L44X		Mask Set 1M88B		Unit
			Min	Max	Min	Max	
—	Internal bus clock (APBCLK)	$F_{CORE}/2$	—	100	—	133	MHz
—	Internal bus clock period (1/APBCLK)	T_{APBCLK}	10.0	—	7.52	—	ns
400	URXD and UTXD inputs high/low duration	$16 \times T_{APBCLK}$	160.0	—	120.3	—	ns
401	URXD and UTXD inputs rise/fall time		—	5	—	5	ns
402	UTXD output rise/fall time		—	5	—	5	ns

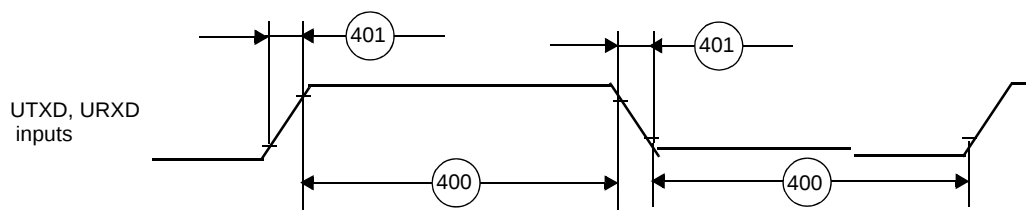


Figure 21. UART Input Timing

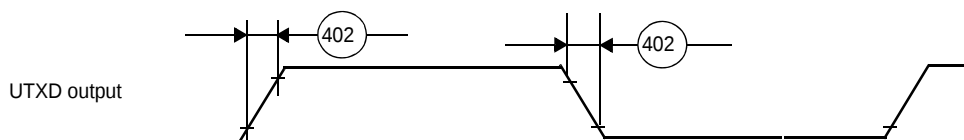


Figure 22. UART Output Timing

2.5.10 EE Timing

Table 28. EE0 Timing

Number	Characteristics	Type	Min
65	EE0 input to the core	Asynchronous	4 core clock periods
66	EE0 output from the core	Synchronous to core clock	1 core clock period

Notes:

1. The core clock is the SC1400 core clock. The ratio between the core clock and CLKOUT is configured during power-on-reset.
2. Configure the direction of the EE pin in the EE_CTRL register (see the *SC1400 Core Reference Manual* for details).
3. Refer to **Table 14** for details on EE pin functionality.

Figure 23 shows the signal behavior of the EE pin.

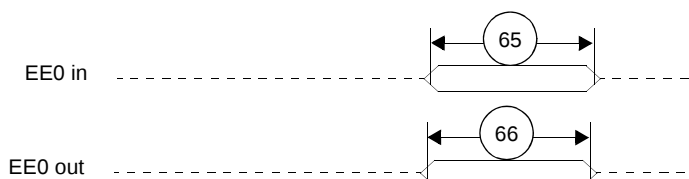


Figure 23. EE Pin Timing

2.5.11 Event Timing

Table 29. EVNT Signal Timing

Number	Characteristics	Type	Min
67	EVNT as input	Asynchronous	$1.5 \times \text{APBCLK periods}$
68	EVNT as output	Synchronous to core clock	1 APBCLK period
Notes: 1. Refer to Table 27 for a definition of the APBCLK period. 2. Direction of the EVNT signal is configured through the GPIO and Event port registers. 3. Refer to the <i>MSC711x Reference Manual</i> for details on EVNT pin functionality.			

Figure 24 shows the signal behavior of the EVNT pin.

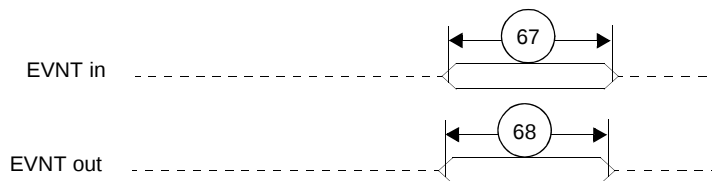


Figure 24. EVNT Pin Timing

2.5.12 GPIO Timing

Table 30. GPIO Signal Timing^{1,2,3}

Number	Characteristics	Type	Min
601	GPI ^{4,5}	Asynchronous	$1.5 \times \text{APBCLK periods}$
602	GPO ⁵	Synchronous to core clock	1 APBCLK period
603	Port A edge-sensitive interrupt	Asynchronous	$1.5 \times \text{APBCLK periods}$
604	Port A level-sensitive interrupt	Asynchronous	$3 \times \text{APBCLK periods}^6$
Notes: 1. Refer to Table 27 for a definition of the APBCLK period. 2. Direction of the GPIO signal is configured through the GPIO port registers. 3. Refer to <i>MSC711x Reference Manual</i> for details on GPIO pin functionality. 4. GPI data is synchronized to the APBCLK internally and the minimum listed is the capability of the hardware to capture data into a register when the GPA_DR is read. The specification is not tested due to the asynchronous nature of the input and dependence on the state of the DSP core. It is guaranteed by design. 5. The input and output signals cannot toggle faster than 50 MHz. 6. Level-sensitive interrupts should be held low until the system determines (via the service routine) that the interrupt is acknowledged.			

Figure 25 shows the signal behavior of the GPI/GPO pin.

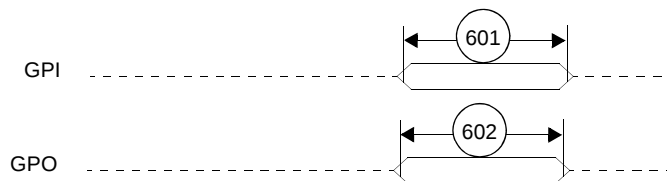


Figure 25. GPI/GPO Pin Timing

2.5.13 JTAG Signals

Table 31. JTAG Timing

No.	Characteristics	All frequencies		Unit
		Min	Max	
700	TCK frequency of operation ($1/(T_C \times 3)$; maximum 22 MHz)	0.0	40.0	MHz
701	TCK cycle time	25.0	—	ns
702	TCK clock pulse width measured at $V_M = 1.6$ V	11.0	—	ns
703	TCK rise and fall times	0.0	3.0	ns
704	Boundary scan input data set-up time	5.0	—	ns
705	Boundary scan input data hold time	14.0	—	ns
706	TCK low to output data valid	0.0	20.0	ns
707	TCK low to output high impedance	0.0	20.0	ns
708	TMS, TDI data set-up time	5.0	—	ns
709	TMS, TDI data hold time	25.0	—	ns
710	TCK low to TDO data valid	0.0	24.0	ns
711	TCK low to TDO high impedance	0.0	10.0	ns
712	$\overline{\text{TRST}}$ assert time	100.0	—	ns
Note: All timings apply to OCE module data transfers as the OCE module uses the JTAG port as an interface.				

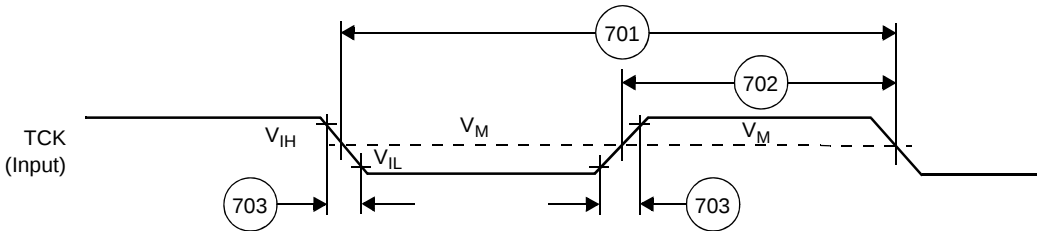


Figure 26. Test Clock Input Timing Diagram

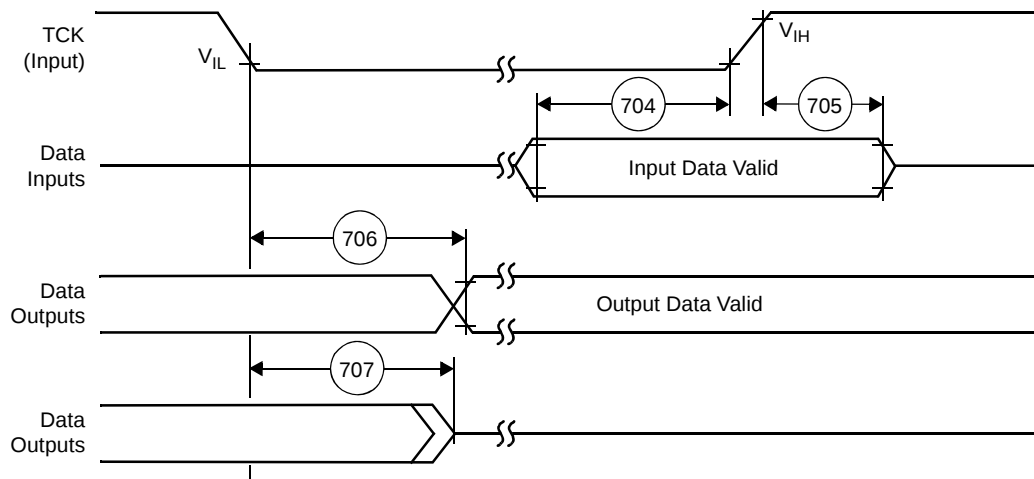


Figure 27. Boundary Scan (JTAG) Timing Diagram

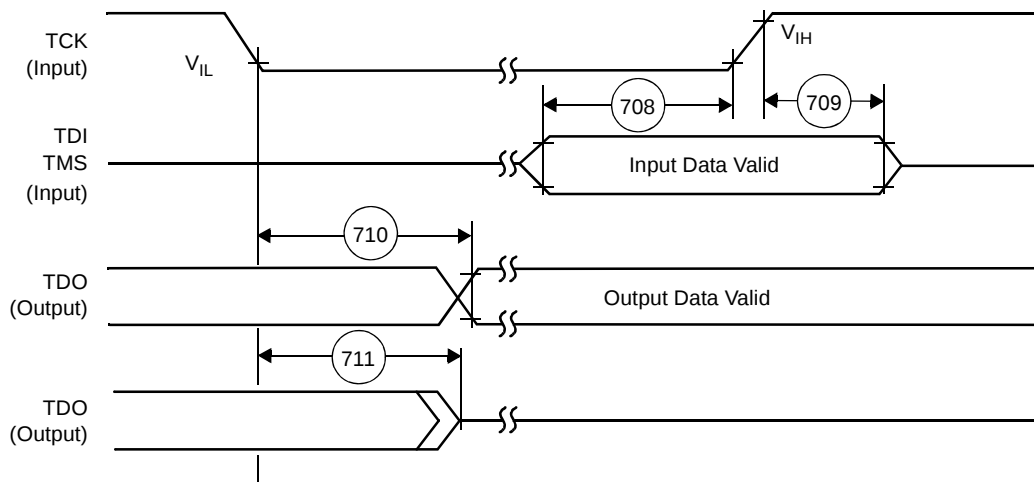


Figure 28. Test Access Port Timing Diagram



Figure 29. $\overline{\text{TRST}}$ Timing Diagram

3 Hardware Design Considerations

This section describes various areas to consider when incorporating the MSC7113 device into a system design.

3.1 Thermal Design Considerations

An estimation of the chip-junction temperature, T_J , in °C can be obtained from the following:

$$T_J = T_A + (R_{\theta JA} \times P_D) \quad \text{Eqn. 1}$$

where

T_A = ambient temperature near the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

$P_D = P_{INT} + P_{I/O}$ = power dissipation in the package (W)

$P_{INT} = I_{DD} \times V_{DD}$ = internal power dissipation (W)

$P_{I/O}$ = power dissipated from device on output pins (W)

The power dissipation values for the MSC7113 are listed in **Table 4**. The ambient temperature for the device is the air temperature in the immediate vicinity that would cool the device. The junction-to-ambient thermal resistances are JEDEC standard values that provide a quick and easy estimation of thermal performance. There are two values in common usage: the value determined on a single layer board and the value obtained on a board with two planes. The value that more closely approximates a specific application depends on the power dissipated by other components on the printed circuit board (PCB). The value obtained using a single layer board is appropriate for tightly packed PCB configurations. The value obtained using a board with internal planes is more appropriate for boards with low power dissipation (less than 0.02 W/cm² with natural convection) and well separated components. Based on an estimation of junction temperature using this technique, determine whether a more detailed thermal analysis is required. Standard thermal management techniques can be used to maintain the device thermal junction temperature below its maximum. If T_J appears to be too high, either lower the ambient temperature or the power dissipation of the chip.

You can verify the junction temperature by measuring the case temperature using a small diameter thermocouple (40 gauge is recommended) or an infrared temperature sensor on a spot on the device case. Use the following equation to determine T_J :

$$T_J = T_T + (\Psi_{JT} \times P_D) \quad \text{Eqn. 2}$$

where

T_T = thermocouple (or infrared) temperature on top of the package (°C)

Ψ_{JT} = thermal characterization parameter (°C/W)

P_D = power dissipation in the package (W)

3.2.2.1 Case 1

The power-up sequence is as follows:

1. Turn on the V_{DDIO} (3.3 V) supply first.
2. Turn on the V_{DDC} (1.2 V) supply second.
3. Turn on the V_{DDM} (2.5 V) supply third.
4. Turn on the V_{REF} (1.25 V) supply fourth (last).

The power-down sequence is as follows:

1. Turn off the V_{REF} (1.25 V) supply first.
2. Turn off the V_{DDM} (2.5 V) supply second.
3. Turn off the V_{DDC} (1.2 V) supply third.
4. Turn of the V_{DDIO} (3.3 V) supply fourth (last).

Use the following guidelines:

- Make sure that the time interval between the ramp-down of V_{DDIO} and V_{DDC} is less than 10 ms.
- Make sure that the time interval between the ramp-up or ramp-down for V_{DDC} and V_{DDM} is less than 10 ms for power-up and power-down.
- Refer to **Figure 30** for relative timing for power sequencing case 1.

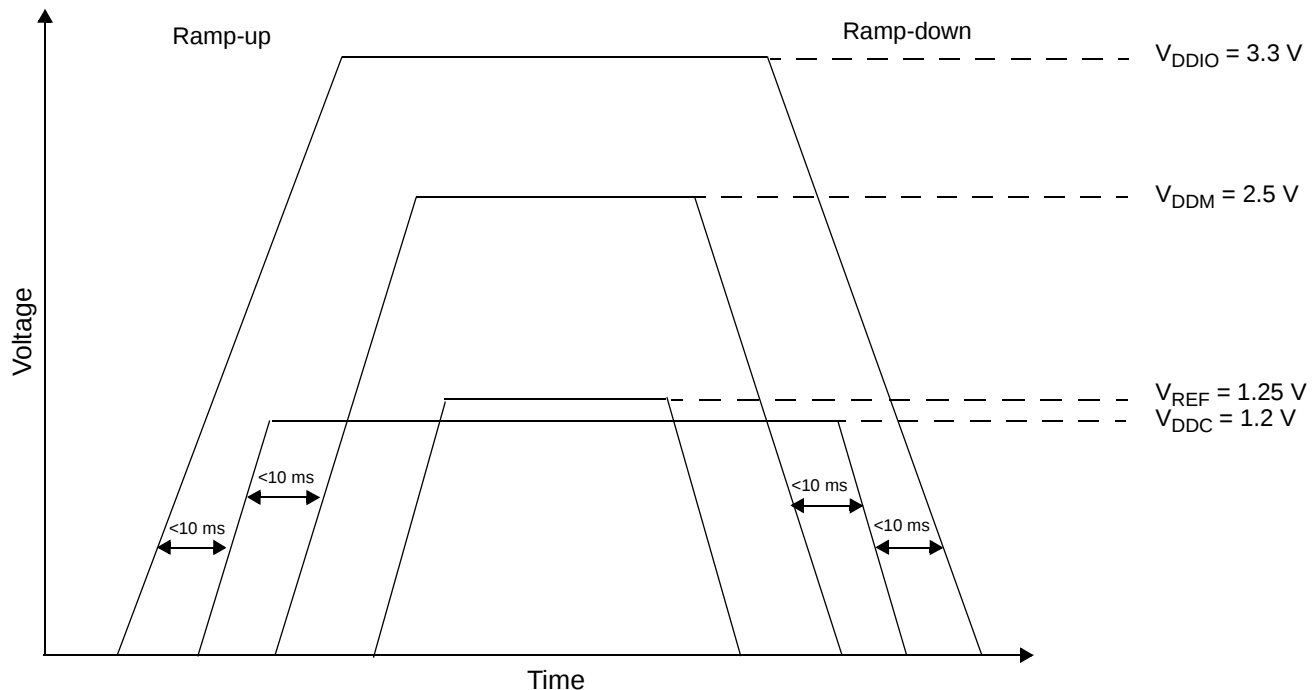


Figure 30. Voltage Sequencing Case 1

3.2.2.2 Case 2

The power-up sequence is as follows:

1. Turn on the V_{DDIO} (3.3 V) supply first.
2. Turn on the V_{DDC} (1.2 V) and V_{DDM} (2.5 V) supplies simultaneously (second).
3. Turn on the V_{REF} (1.25 V) supply last (third).

Note: Make sure that the time interval between the ramp-up of V_{DDIO} and V_{DDC}/V_{DDM} is less than 10 ms.

The power-down sequence is as follows:

1. Turn off the V_{REF} (1.25 V) supply first.
2. Turn off the V_{DDM} (2.5 V) supply second.
3. Turn off the V_{DDC} (1.2 V) supply third.
4. Turn of the V_{DDIO} (3.3 V) supply fourth (last).

Use the following guidelines:

- Make sure that the time interval between the ramp-down for V_{DDIO} and V_{DDC} is less than 10 ms.
- Make sure that the time interval between the ramp-up or ramp-down for V_{DDC} and V_{DDM} is less than 10 ms for power-up and power-down.
- Refer to **Figure 31** for relative timing for Case 2.

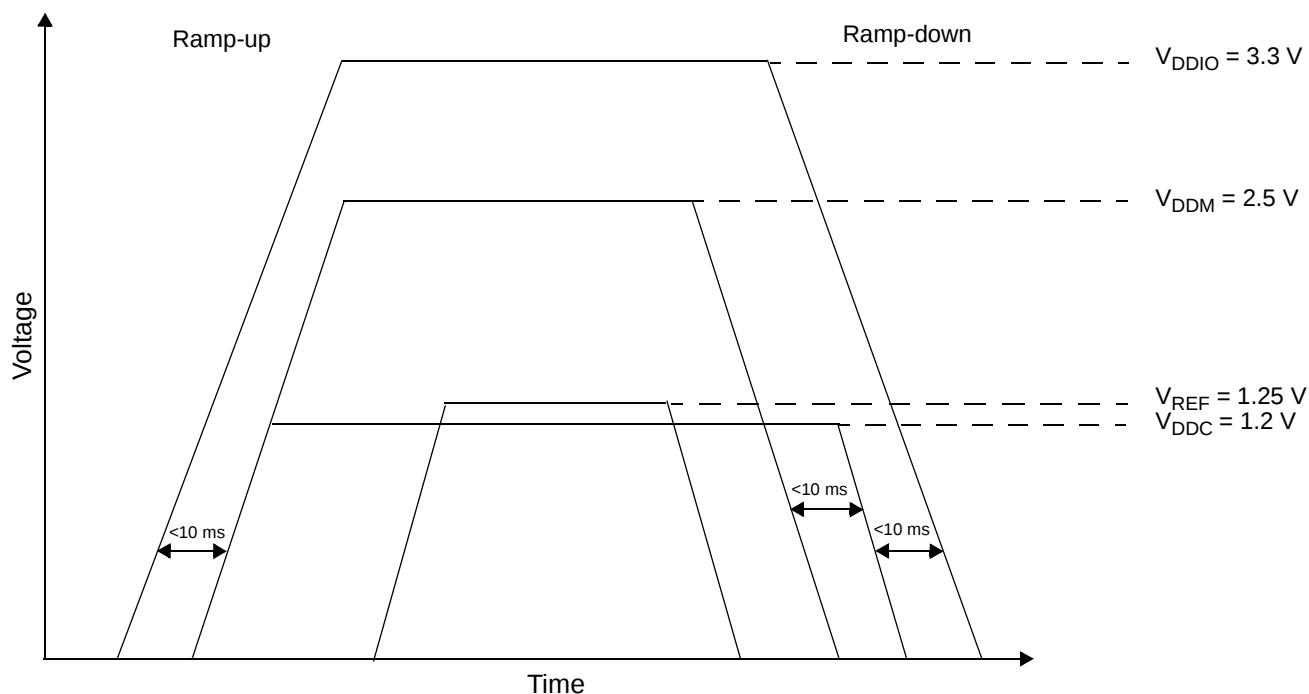


Figure 31. Voltage Sequencing Case 2

3.2.3 Power Planes

Each power supply pin (V_{DDC} , V_{DDM} , and V_{DDIO}) should have a low-impedance path to the board power supply. Each GND pin should be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on the device. The MSC7113 V_{DDC} power supply pins should be bypassed to ground using decoupling capacitors. The capacitor leads and associated printed circuit traces connecting to device power pins and GND should be kept to less than half an inch per capacitor lead. A minimum four-layer board that employs two inner layers as power and GND planes is recommended. See **Section 3.5** for DDR Controller power guidelines.

3.2.4 Decoupling

Both the I/O voltage and core voltage should be decoupled for switching noise. For I/O decoupling, use standard capacitor values of $0.01\ \mu\text{F}$ for every two to three voltage pins. For core voltage decoupling, use two levels of decoupling. The first level should consist of a $0.01\ \mu\text{F}$ high frequency capacitor with low effective series resistance (ESR) and effective series inductance (ESL) for every two to three voltage pins. The second decoupling level should consist of two bulk/tantalum decoupling capacitors, one $10\ \mu\text{F}$ and one $47\ \mu\text{F}$, (with low ESR and ESL) mounted as closely as possible to the MSC7113 voltage pins. Additionally, the maximum drop between the power supply and the DSP device should be $15\ \text{mV}$ at $1\ \text{A}$.

3.2.5 PLL Power Supply Filtering

The MSC7113 V_{DDPLL} power signal provides power to the clock generation PLL. To ensure stability of the internal clock, the power supplied to this pin should be filtered with capacitors that have low and high frequency filtering characteristics. V_{DDPLL} can be connected to V_{DDC} through a $2\ \Omega$ resistor. V_{SSPLL} can be tied directly to the GND plane. A circuit similar to the one shown in **Figure 35** is recommended. The PLL loop filter should be placed as closely as possible to the V_{DDPLL} pin (which are located on the outside edge of the silicon package) to minimize noise coupled from nearby circuits. The $0.01\ \mu\text{F}$ capacitor should be closest to V_{DDPLL} , followed by the $0.1\ \mu\text{F}$ capacitor, the $10\ \mu\text{F}$ capacitor, and finally the $2\text{-}\Omega$ resistor to V_{DDC} . These traces should be kept short.

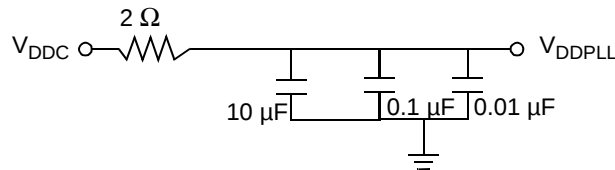


Figure 35. PLL Power Supply Filter Circuits

3.2.6 Power Consumption

You can reduce power consumption in your design by controlling the power consumption of the following regions of the device:

- *Extended core.* Use the SC1400 Stop and Wait modes by issuing a **stop** or **wait** instruction.
- *Clock synthesis module.* Disable the PLL, timer, watchdog, or DDR clocks or disable the CLK0 pin.
- *AHB subsystem.* Freeze or shut down the AHB subsystem using the GPSCTL[XBR_HRQ] bit.
- *Peripheral subsystem.* Halt the individual on-device peripherals such as the DDR memory controller, Ethernet MAC, HDI16, TDM, UART, I²C, and timer modules.

For details, see the “Clocks and Power Management” chapter of the *MSC711x Reference Manual*.

3.3.2 Peripheral Power

Peripherals include the DDR memory controller, DMA controller, HDI16, TDM, UART, timers, GPIOs, and the I²C module. Basic power consumption by each module is assumed to be the same and is computed by using the following equation which assumes an effective load of 20 pF, core voltage swing of 1.2 V, and a switching frequency of 100 MHz or 133 MHz. This yields:

$$P_{PERIPHERAL} = 20 \text{ pF} \times (1.2 \text{ V})^2 \times 100 \text{ MHz} \times 10^{-3} = 2.88 \text{ mW per peripheral} \quad \text{Eqn. 7}$$

$$P_{PERIPHERAL} = 20 \text{ pF} \times (1.2 \text{ V})^2 \times 133 \text{ MHz} \times 10^{-3} = 3.83 \text{ mW per peripheral} \quad \text{Eqn. 8}$$

Multiply this value by the number of peripherals used in the application to compute the total peripheral power consumption.

3.3.3 External Memory Power

Estimation of power consumption by the DDR memory system is complex. It varies based on overall system signal line usage, termination and load levels, and switching rates. Because the DDR memory includes terminations external to the MSC7113 device, the 2.5 V power source provides the power for the termination, which is a static value of 16 mA per signal driven high. The dynamic power is computed, however, using a differential voltage swing of $\pm 0.200 \text{ V}$, yielding a peak-to-peak swing of 0.4 V. The equations for computing the DDR power are:

$$P_{DDRIO} = P_{STATIC} + P_{DYNAMIC} \quad \text{Eqn. 9}$$

$$P_{STATIC} = (\text{unused pins} \times \% \text{ driven high}) \times 16 \text{ mA} \times 2.5 \text{ V} \quad \text{Eqn. 10}$$

$$P_{DYNAMIC} = (\text{pin activity value}) \times 20 \text{ pF} \times (0.4 \text{ V})^2 \times 200 \text{ MHz} \times 10^{-3} \text{ mW} \quad \text{Eqn. 11}$$

$$P_{DYNAMIC} = (\text{pin activity value}) \times 20 \text{ pF} \times (0.4 \text{ V})^2 \times 266 \text{ MHz} \times 10^{-3} \text{ mW} \quad \text{Eqn. 12}$$

$$\text{pin activity value} = (\text{active data lines} \times \% \text{ activity} \times \% \text{ data switching}) + (\text{active address lines} \times \% \text{ activity}) \quad \text{Eqn. 13}$$

As an example, assume the following:

- unused pins = 16 (DDR uses 16-pin mode)
- % driven high = 50%
- active data lines = 16
- % activity = 60%
- % data switching = 50%
- active address lines = 3

In this example, the DDR memory power consumption is:

$$P_{DDRIO} = ((16 \times 0.5) \times 16 \times 2.5) + (((16 \times 0.6 \times 0.5) + (3 \times 0.6)) \times 20 \times (0.4)^2 \times 200 \times 10^{-3}) = 324.2 \text{ mW} \quad \text{Eqn. 14}$$

$$P_{DDRIO} = ((16 \times 0.5) \times 16 \times 2.5) + (((16 \times 0.6 \times 0.5) + (3 \times 0.6)) \times 20 \times (0.4)^2 \times 266 \times 10^{-3}) = 326.3 \text{ mW} \quad \text{Eqn. 15}$$

3.3.4 External I/O Power

The estimation of the I/O power is similar to the computation of the peripheral power estimates. The power consumption per signal line is computed assuming a maximum load of 20 pF, a voltage swing of 3.3 V, and a switching frequency of 25 MHz or 33 MHz, which yields:

$$P_{IO} = 20 \text{ pF} \times (3.3 \text{ V})^2 \times 25 \text{ MHz} \times 10^{-3} = 5.44 \text{ mW per I/O line} \quad \text{Eqn. 16}$$

$$P_{IO} = 20 \text{ pF} \times (3.3 \text{ V})^2 \times 33 \text{ MHz} \times 10^{-3} = 7.19 \text{ mW per I/O line} \quad \text{Eqn. 17}$$

Multiply this number by the number of I/O signal lines used in the application design to compute the total I/O power.

Note: The signal loading depends on the board routing. For systems using a single DDR device, the load could be as low as 7 pF.

3.3.5 Leakage Power

The leakage power is for all power supplies combined at a specific temperature. The value is temperature dependent. The observed leakage value at room temperature is 64 mW.

3.3.6 Example Total Power Consumption

Using the examples in this section and assuming four peripherals and 10 I/O lines active, a total power consumption value is estimated as the following:

$$P_{TOTAL} (200 \text{ MHz core}) = 216 + (4 \times 2.88) + 324.2 + (10 \times 5.44) + 64 = 670.12 \text{ mW} \quad \text{Eqn. 18}$$

$$P_{TOTAL} (266 \text{ MHz core}) = 287 + (4 \times 3.83) + 326.3 + (10 \times 7.19) + 64 = 764.52 \text{ mW} \quad \text{Eqn. 19}$$

3.4 Reset and Boot

This section describes the recommendations for configuring the MSC7113 at reset and boot.

3.4.1 Reset Circuit

$\overline{\text{HRESET}}$ is a bidirectional signal and, if driven as an input, should be driven with an open collector or open-drain device. For an open-drain output such as $\overline{\text{HRESET}}$, take care when driving many buffers that implement input bus-hold circuitry. The bus-hold currents can cause enough voltage drop across the pull-up resistor to change the logic level to low. Either a smaller value of pull-up or less current loading from the bus-hold drivers overcomes this issue. To avoid exceeding the MSC7113 output current, the pull-up value should not be too small (a 1 K Ω pull-up resistor is used in the MSC711xADS reference design).

3.4.2 Reset Configuration Pins

Table 34 shows the MSC7113 reset configuration signals. These signals are sampled at the deassertion (rising edge) of $\overline{\text{PORESET}}$. For details, refer to the Reset chapter of the *MSC711x Reference Manual*.

Table 34. Reset Configuration Signals

Signal	Description	Settings
BM[1–0]	Determines boot mode.	0 Boot from HDI16 port. 01 Boot from I2C. 1x Reserved.
SWTE	Determines watchdog functionality.	0 Watchdog timer disabled. 1 Watchdog timer enabled.
HDSP	Configures HDI16 strobe polarity.	0 Host Data strobes active low. 1 Host Data strobes active high.
H8BIT	Configures HDI16 operation mode.	0 HDI16 port configured for 16-bit operation. 1 HDI16 port configured for 8-bit operation.

3.4.3 Boot

After a power-on reset, the PLL is bypassed and the device is directly clocked from the CLKIN pin. Using this input clock, the system initializes using the boot loader program that resides in the internal ROM. After initialization, the DSP core can enable the PLL and start the device operating at a higher speed. The MSC7113 can boot from an external host through the HDI16 or download a user program through the I²C port. The boot operating mode is set by configuring the BM[1–0] signals sampled at the rising edge of $\overline{\text{PORESET}}$, as shown in **Table 35**.

Table 35. Boot Mode Settings

BM1	BM0	Boot Source
0	0	External host via HDI16 with the PLL disabled.
0	1	I ² C.
1	0	External host via the HDI16 with the PLL enabled.
1	1	Reserved.

3.4.3.1 HDI16 Boot

If the MSC7113 device boots from an external host through the HDI16, the port is configured as follows:

- Operate in Non-DMA mode.
- Operate in polled mode on the device side.
- Operate in polled mode on the external host side.
- External host must write four 16-bit values at a time with the first word as the most significant and the fourth word as the least significant.

When booting from a power-on reset, the HDI16 is additionally configurable as follows:

- 8- or 16-bit mode as specified by the H8BIT pin.
- Data strobe as specified by the HDSP and HDDS pins.

These pins are sampled only on the deassertion of power-on reset. During a boot from a hard reset, the configuration of these pins is unaffected.

Note: When the HDI16 is used for booting or other purposes, bit 0 is the least significant bit and not the most significant bit as for other DSP products.